

: Atty. Docket No. : Serial No.
: HSJ920030181US1: not yet assigned
: Applicant(s)
: S. Duan et al.
: File Date 8/1/03 : Group 2862
: Herewith : not yet assigned

LIST OF PRIOR ART CITED BY APPLICANT(S)
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

EXAM.:	: DOCUMENT			CLASS/	FILING
INTL.:	: NUMBER	DATE	NAME	SUBCLASS	DATE
<i>RA</i>	:AA: 2003/0038626A1	02/27/03	C. Carrington et al.	324/210	08/23/01
<i>RA</i>	:AB: 6,519,108B2	02/11/03	H.A. Au et al.	360/77.04	12/01/99
<i>RA</i>	:AC: 6,489,762B2	12/03/02	G. Wang et al.	324/210	04/26/01
<i>RA</i>	:AD: 2002/0113587A1	08/22/02	J. Kim	324/210	02/12/02
<i>RA</i>	:AE: 6,400,519B2	06/04/02	N. Mukoyama	360/31	01/31/01
<i>RA</i>	:AF: 6,373,647B1	04/16/02	B.R. Baker	360/25	11/12/99
<i>RA</i>	:AG: 2003/0030934A1	02/13/03	M.D. Schaff	360/66	01/24/02
<i>RA</i>	:AH: 2002/0063984A1	05/30/02	B.A. McClellan	360/46	10/29/01
<i>RA</i>	:AI: 6,295,175B1	09/25/01	I. Tomita et al.	360/31	12/22/98
<i>RA</i>	:AJ: 6,249,392B1	06/19/01	A. H. Sacks et al.	360/31	05/13/98
<i>RA</i>	:AK: 6,081,114	06/27/00	K. Shimazawa et al.	324/210	02/17/98
<i>RA</i>	:AL: 5,998,993	12/07/99	K. Inage et al.	324/210	03/06/98
<i>RA</i>	:AM: 5,640,089	06/17/97	J. Horikawa et al.	324/212	09/11/95

FOREIGN DOCUMENTS

					<i>Abstract</i>
: DOC. NO.	: DATE	: COUNTRY	: CLASS/	: TRANSLATION	
:	:	:	: SUBCLASS	YES : NO	
<i>RA</i> :BA: JP92002025024	01/25/02	Japan	G11B5/455	X	
<i>RA</i> :BB: JP92001006133	01/12/01	Japan	G11B5/455	X	
<i>RA</i> :BC: JP6309636	11/04/94	Japan	G11B5/455	X	
<i>RA</i> :BD: JP2080975	03/22/90	Japan	G01R31/00	X	

OTHER PRIOR ART (INCLUD. AUTHOR, TITLE, DATE, PERTINENT PG., ETC.)

RA :CA: A. Wallash, "New Early Failure Phenomenon in Electrostatic Discharge Damaged Giant Magnetoresistive Recording Heads", Journal of Applied Physics, Vol. 93, No. 10, May 15, 2003, pp. 7319-7321

EXAMINER

Leena Aurora

DATE CONSIDERED

3/22/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).